May 1998

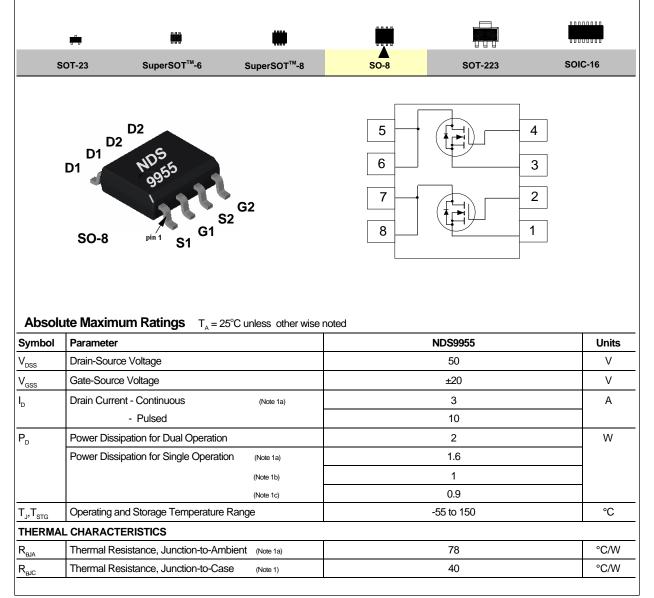
NDS9955 Dual N-Channel Enhancement Mode Field Effect Transistor

General Description

SO-8 N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, high cell density, DMOS technology. This very high density process is especially tailored to provide superior switching performance and minimize on-state resistance. These devices are particularly suited for low voltage applications such as disk drive motor control, battery powered circuits where fast switching, low in-line power loss, and resistance to transients are needed.

Features

- High density cell design for extremely low R_{DS(ON)}.
- High power and current handling capability in a widely used surface mount package.
- Dual MOSFET in surface mount package.

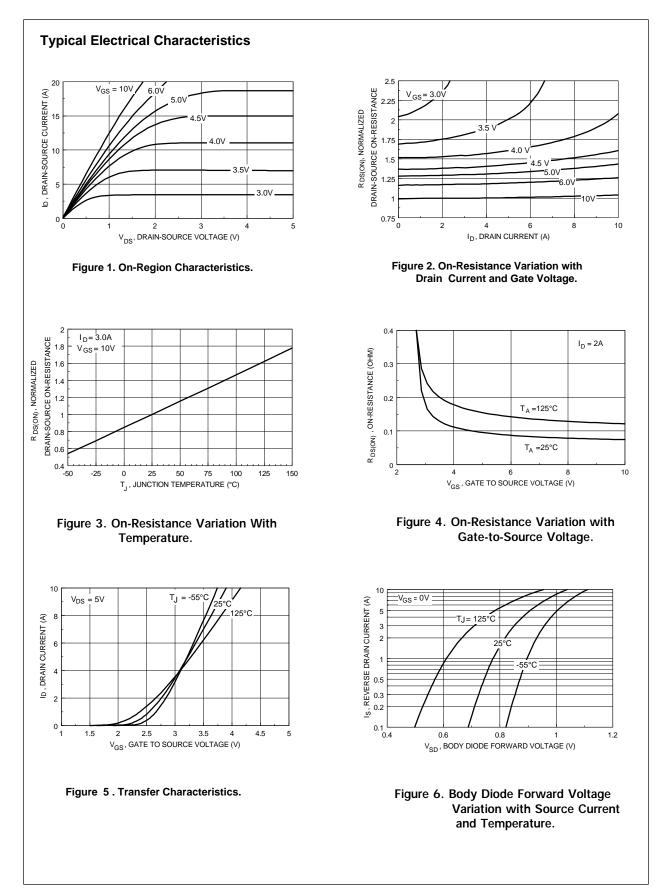


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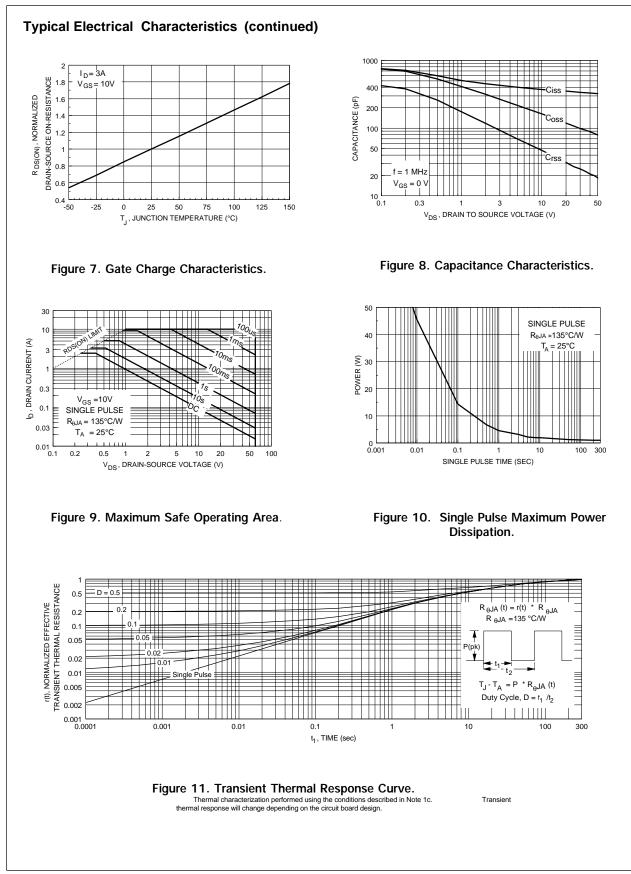
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Symbol	Parameter	Conditions		Min	Тур	Max	Units
OFF CHAR	ACTERISTICS						1
BV _{DSS}	Drain-Source Breakdown Voltage	$V_{GS} = 0 V, I_{D} = 250 \mu A$		50			V
$\Delta BV_{DSS} / \Delta T_{J}$	Breakdown Voltage Temp. Coefficient	$I_p = 250 \mu$ A, Referenced to 25 °C			60		mV/ °C
I _{DSS}	Zero Gate Voltage Drain Current	$V_{\rm DS} = 40 \text{V}, V_{\rm GS} = 0 \text{V}$				2	μA
	Gate - Body Leakage, Forward	$V_{gs} = 20 \text{ V}, \text{ V}_{gs} = 0 \text{ V}$				100	nA
GSSR	Gate - Body Leakage, Reverse	$V_{GS} = -20 \text{ V}, V_{DS} = 0 \text{ V}$				-100	nA
	CTERISTICS (Note 2)	63 / 53		1			
V _{GS(th)}	Gate Threshold Voltage $V_{DS} = V_{GS}$, $I_D = 250 \mu A$		1	1.7	3	V	
	ů,		T_ =125°C	0.7		2.2	
R _{DS(ON)}	Static Drain-Source On-Resistance	$V_{GS} = 10 \text{ V}, \text{ I}_{D} = 3 \text{ A}$	J		0.076	0.13	Ω
			T_ =125°C		0.124	0.2	
		$V_{GS} = 4.5 \text{ V}, \text{ I}_{D} = 1.5 \text{ A}$	5		0.103	0.2	
			T_ =125°C		0.166	0.3	_
l _{D(ON)}	On-State Drain Current	$V_{GS} = 10 \text{ V}, V_{DS} = 10 \text{ V}$	3	10		-	А
9 _{FS}	Forward Transconductance	$V_{\rm DS} = 10 \text{ V}, \text{ I}_{\rm D} = 3 \text{ A}$			5.3		S
-	CH ARACTERISTICS	50 5		1			1
C _{iss}	Input Capacitance	$V_{DS} = 25 V, V_{GS} = 0 V,$ f = 1.0 MHz			345		pF
C _{oss}	Output Capacitance				110		pF
C _{rss}	Reverse Transfer Capacitance				25		pF
	G CHARACTERISTICS (Note 2)						
t _{D(on)}	Turn - On Delay Time	$V_{DS} = 25 \text{ V}, \text{ I}_{D} = 1 \text{ A}$ $V_{GS} = 10 \text{ V}, \text{ R}_{GEN} = 6 \Omega$			5	20	ns
t,	Turn - On Rise Time				7.5	20	
t _{D(off)}	Turn - Off Delay Time				20	70	
t,	Turn - Off Fall Time				7	5	
Q _q	Total Gate Charge	$V_{DS} = 25 \text{ V}, \text{ I}_{D} = 2 \text{ A},$	$V_{DS} = 25 V, I_{D} = 2 A,$		12.9	30	nC
Q _{gs}	Gate-Source Charge	V _{GS} = 10 V			1.7		1
Q _{qd}	Gate-Drain Charge				3.2		
ě.	IRCE DIODE CHARACTERISTICS AND MA	XIMUM RATINGS					
s	Maximum Continuous Drain-Source Diode F	orward Current				1.3	А
V _{SD}	Drain-Source Diode Forward Voltage	$V_{GS} = 0 \text{ V}, \text{ I}_{S} = 1.3 \text{ A}$ (Note	e 2)		0.8	1.2	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 V, I_F = 1.3 A,$ $dI_F/dt = 100 A/\mu s$			40		ns
l _{rr}	Reverse Recovery Current				1.5		Α
	m of the junction-to-case and case-to-ambient thermal resistance R _{ecA} is determined by the user's board design.	where the case thermal reference is defined	Q	ing surface	Q	ins. R _{θuc} is gι 35 [°] C/W on a	

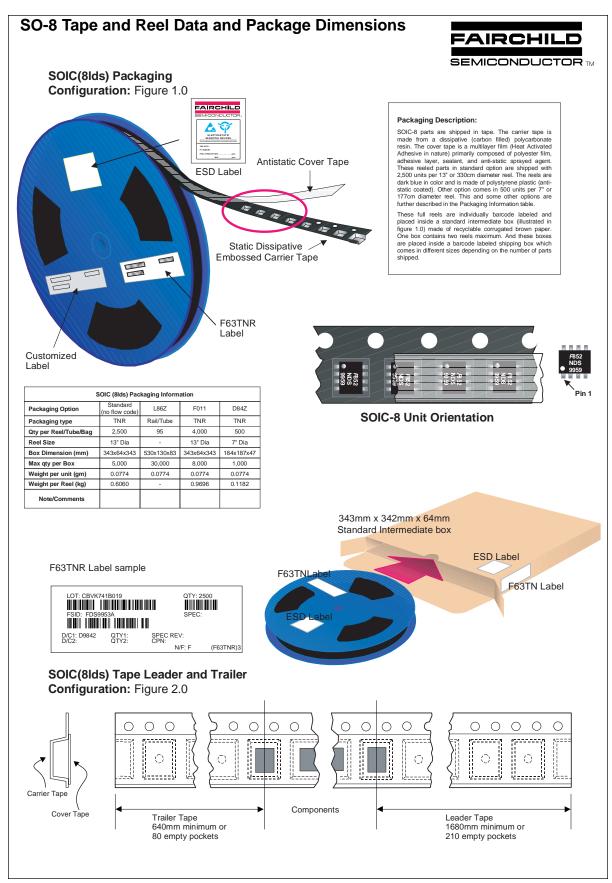
2. Pulse Test: Pulse Width \leq 300µs, Duty Cycle \leq 2.0%.



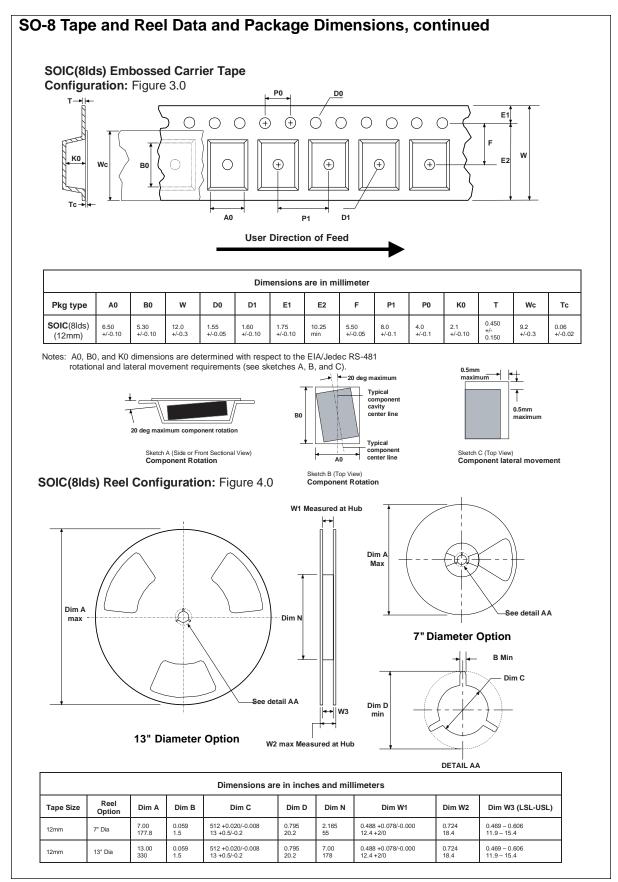
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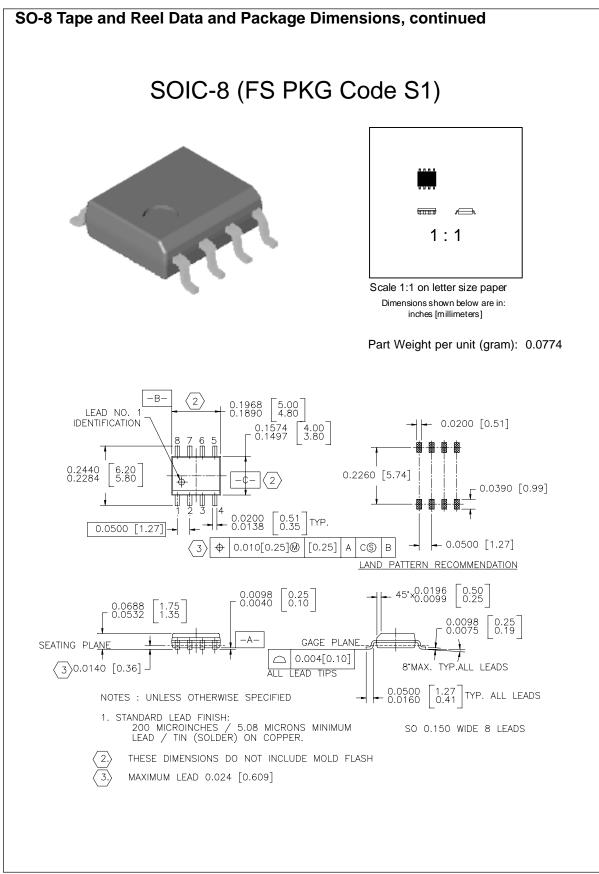
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September 1998, Rev. A

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